



TESTFORUM 2013

Swissôtel, Tallinn, Estonia
November 26th & 27th, 2013

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Test Forum 2013 Local Organizer

Artur Jutman
Tallinn University of Technology
Phone: +372 620 2246
Fax: +372 620 2253
E-mail: artur@pld.ttu.ee

Call for Papers / Presentations

The 2-day TestForum 2013, the 14th event in the series, is a major event for Test professionals in the Nordic area and Baltic states. Every year the TestForum is attended by key people from the industry's test community as well as by international vendors of test and measurement equipment and solutions.

The event will take place in Swissôtel, which is located in the downtown of Tallinn nearby its medieval historic center.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2013, which includes (but is not limited to) the following topics:

- *Functional Test*
- *Boundary Scan*
- *Embedded Instruments*
- *RF Testing*
- *AOI / AXI / SPI*
- *ICT / Flying Probe*
- *Test economics*
- *Power Test*
- *Fixturing/Interfaces*
- *Future technology trends and test challenges*
- *Best practices in manufacturing test*
- *ASIC: BIST / Mixed-signal / IDDQ / IDDT*
- *Board test SW, BIST, diagnostics*
- *Quality methods and tools*
- *Preventive test / Prognostics*
- *Design to Test transfer / Design for Test*
- *ESD*
- *Test efficiency and optimization*
- *Data acquisition / collection / analysis*

Submissions

NTF seeks for full papers and/or presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities, techniques and best practices in electronics test technology rather than on particular products.

Proceedings

The accepted contributions of authors that wish to provide the corresponding materials will be delivered in electronic format at the Nordic Test Forum event.

The Format of the Event

- The event format will be a two-day workshop and a small exhibition attached to it.
- November 25th on the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- Poster display of selected material – a recommended option at the breaks after each session - will allow each presenter to obtain more focus on his/her presentation.
- In exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

Key Dates

- Abstract submission: **September 16th, 2013**
- Notification of acceptance: **September 30th, 2013**
- Conference Registration: **October 28th, 2013**
- Presentation slides: **October 31st, 2013**

Further Information and Submissions

Suzanne Holte
Phone: +45 2088 5972
Email: suzanne@nordicestforum.org

Visit the NTF web pages at:
<http://www.nordicestforum.org>

